Title: Qualification of UTAC as an alternate Assembly and test site for the TPS22990NDMLF Customer Contact: PCN Manager Dept: Quality Services Proposed 1 st Ship Date: June 22 2019 Estimated Sample Availability: Date provided at sample request Change Type: Une 22 2019 Estimated Sample Assembly Site Date provided at sample request Assembly Site Design Wafer Bump Site Assembly Process Data Sheet Wafer Bump Material Assembly Materials Part number change Wafer Bump Process Mechanical Specification Test Site Wafer Fab Site Packing/Shipping/Labeling Test Process Wafer Fab Materials Description of Change: PCN Details Description of Change: Vaterial differences are as follows: Mold Compound 4208625 SID#C20288 Mount Compound (NexFET - Conductive) 4206201 SID#PZ0035 Mount Compound (LBC7 - Non-Conductive) 4221460 SID#PZ0076 Bond Wire (LBC7 to FET & LF) Cu, 0.8 mils Cu, 1.0 mils Lead Finish NiPdAu NiPdAu					
Proposed 1 st Ship Date: June 22 2019 Estimated Sample Availability: Date provided at sample request Change Type:					
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Lead Finish NiPdAu NiPdAuAg					
Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ. Reason for Change: Continuity of Supply Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative): None					
Anticipated impact on Material Declaration					
Anticipated impact on Material Declaration No Impact to the Material Declarations or Product Content reports are driven from production data and will be available following the production release. Upon production release the revised reports can be obtained at the site link below http://www.ti.com/quality/docs/materialcontentsearch.tsp					
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No Impact to the Material Declaration Material Declarations or Product Content reports are driven from production data and will be available following the production release. Upon production release the revised reports can be obtained at the site link below <u>http://www.ti.com/quality/docs/materialcontentsearch.tsp</u> Changes to product identification resulting from this PCN:					

Sample product shipping label (not actual product label)					
INSTRUMENTS G4 2DC: 2Q: MADE IN: Malaysia Q: 2DC: 2Q: MSL '2 /260C/1 YEAR SEAL DT 03/29/04 OPT: 03/29/04 OPT: 39 LBL: 5A (L)T0:1750					
Product Affected:					
TPS22990NDMLR	TPS22990NDMLT				

TEXAS INSTRUMENTS

TI Information Selective Disclosure

Qualification Report

Approve Date 12-Mar-2019

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	QBS Product Reference: <u>TPS22990DMLR</u>
AC	Autoclave 121C	96 hours	3/231/0
CDM	ESD - CDM	1500 V	1/3/0
ED	Electrical Characterization	(Per Datasheet Parameters)	1/Pass
HAST	Biased HAST, 110C/85%RH	264 hours	3/231/0
HTOL	Life Test, 150C	300 hours	1/77/0
HTSL	High Temp Storage Bake 170C	420 hours	3/231/0
PD	Physical Dimensions	(per mechanical drawing)	3/15/0
SD	Solderability	Steam age, 8 hours; PB-Free solder	3/66/0
TC	Temperature Cycle, -65/150C	500 cycles	3/231/0
WBP	Bond Pull	76 Wire, 3 units min	3/228/0
XRAY	X-ray	(top side only)	3/15/0

- QBS: Qual By Similarity

- Qual Device TPS22990NDMLR is qualified at LEVEL2-260C

- Device TPS22990NDMLR contains multiple dies.

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours - The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
WW PCN Team	PCN_ww_admin_team@list.ti.com